

**Search Notes****Application/Control No.**

10/665,259

**Examiner**

Patrick J. Lee

**Applicant(s)/Patent under Reexamination**

WANG ET AL.

**Art Unit**

2878

**SEARCHED**

Class	Subclass	Date	Examiner
250	214.1	11/21/05 11/22/05	PL
257	222, 225		PL
257	233, 257		PL
257	288, 290		PL
257	431		PL
Updated	search	4/3/2006	PL

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Consulted w/ S. Allen AU 2878 CL 250	11/21/2005	PL
East (see attached) - USPAT, US-PGPUB, EPO, JPO, DERWENT	11/21/2005	PL
East (see attached) - USPAT, US-PGPUB, EPO, JPO, DERWENT	11/22/2005	PL
East (see attached) - USPAT, US-PGPUB, EPO, JPO, DERWENT	4/3/2006	PL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
Interference search attached		4/24/2006	PL